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1	5733	chip same wafer same test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:02		
2	14218	((clean or cleaning or cleaned) with (probe or needle or pin))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:03		
3	102	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:33		
4	10042	257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/08/ 11:29		
5	13	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:42		
6	1	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin)) and database	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43		
7	29	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43		
8	5	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and database	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43		
9	0	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43		
10	0	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin)) and database and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43		
11	0	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and database and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:43		
12	2	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48,E21.521,E21.524.ccls. 438/11,14,15,17,18,F0R101,F0R142.ccls. 716/4-6.ccls.) and @pd>"20040827"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/01/ 12:44		
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